Application/Control No. Applicant(s)/Patent Under Reexamination FENG ET AL. Examiner Kahsay Habte Application/Control No. Applicant(s)/Patent Under Reexamination FENG ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kesarwani et al. Tetrahedron Letters 43 (2002) 5579-5581.
	٧	An abstract of Kesarwani et al. Tetrahedron Letters 43 (2002) 5579-5581, from STN CAS search.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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